# Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination DENK, GEORG Examiner | Art Unit | Page 1 of 2

## U.S. PATENT DOCUMENTS

| * |    | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name            | Classification |
|---|----|--|-----------------|-----------------|----------------|
|   | Α  | US-5,467,291                                     | 11-1995         | Fan et al.      | 703/14         |
|   | В  | US-6,530,065                                     | 03-2003         | McDonald et al. | 716/4          |
|   | С  | US-5,930,153                                     | 07-1999         | Melville et al. | 703/14         |
|   | D  | US-  |                 |                 |                |
|   | Е  | US-  |                 |                 |                |
|   | F  | US-  |                 |                 |                |
|   | .G | US-  |                 |                 |                |
|   | Н  | US-  |                 |                 |                |
|   | ı  | US-  |                 |                 |                |
|   | J  | US-  |                 |                 |                |
|   | к  | US-  |                 |                 |                |
|   | L  | US-  |                 |                 |                |
|   | М  | US-  |                 | ·               |                |

## **FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | Ν | -  |                 |         |      |                |
|   | 0 |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | ø |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

### **NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |  |  |  |  |
|---|---|--|--|--|--|--|
|   | U | N. Frohlich et al., A New Approach for Parallel Simulation of VLSI Circuits on a Transistor Level, IEEE Transactions on Circuits and Systems, pages 601-613, June 1998.  |  |  |  |  |
|   | V | L. Trajkovic et al., HomSpice: Simulator with Homotopy Algorithms for Finding DC and Steady-State Solutions of NonLinear Circuits, Proceedings of the 1998 IEEE International Symposium on Circuits and Systems, pages 227-231, June 1998. |  |  |  |  |
|   | w | N. Talwalkar et al., A Power BJT Model for Circuit Simulation, 24th Annual IEEE Power Electronics Specialists Conference, pages 50 - 55, June 1996.  |  |  |  |  |
|   | х | C. Ma et al., A Physically-based Lumped-Charge SCR Model, 24th Annual IEEE Power Electronics Specialists Conference, pages 53 - 59, June 1993.   |  |  |  |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited

| Application/Control No.<br>10/009,979 | Reexamination | Applicant(s)/Patent Under Reexamination DENK, GEORG |  |  |
|---------------------------------------|---------------|---|--|--|
| Examiner                              | Art Unit      |   |  |  |
| A. M. Thompson                        | 2825          | Page 2 of 2   |  |  |

## **U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name | Classification |
|---|---|--|-----------------|------|----------------|
|   | Α | US-  |                 |      |                |
|   | В | US-  |                 |      |                |
|   | С | US-  |                 | ,    |                |
|   | D | US-  |                 |      |                |
|   | Е | US-  |                 |      |                |
|   | F | US-  |                 |      |                |
|   | G | US-  |                 |      |                |
|   | Н | US-  |                 |      |                |
|   | _ | US-  |                 |      |                |
|   | J | US-  |                 |      |                |
|   | к | US-  |                 |      |                |
|   | L | US-  |                 |      |                |
|   | М | US-  |                 |      |                |

#### **FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country  | Name | Classification |
|---|---|--|-----------------|----------|------|----------------|
|   | N |  |                 |          |      |                |
|   | 0 |  |                 |          |      |                |
|   | Р |  |                 |          |      |                |
|   | Q |  |                 | <u> </u> |      |                |
|   | R |  |                 |          |      |                |
|   | S |  | -               |          |      |                |
|   | T |  |                 |          |      |                |

## **NON-PATENT DOCUMENTS**

| TOTAL PROBLEMS |   |   |  |  |  |
|----------------|---|---|--|--|--|
| *              |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)   |  |  |  |
|                | U | C. Ma et al., A Systematic Approach to Modeling of Power Semiconductor Devices Based on Charge Control Principles, 25 <sup>th</sup> Annual IEEE Power Electronics Specialists Conference, pages 31-37, June 1994. |  |  |  |
|                | ٧ | U Wever et al., Parallel Transient Analysis for Circuit Simulation, Proceedings of the Twenty-Ninth Hawaii International Conference on System Sciences, pages 442-447, January 1996.                              |  |  |  |
|                | w | H. Warmers et al., Switch-Level Timing Models in the MOS Simulator BRASIL, Proceedings of the European Design Automation Conference, pages 568-572, March 1990.   |  |  |  |
|                | х | F. lannuzzo et al., Physical CAD Model for High-Voltage IGBTs Based on Lumped-Charge Approach, IEEE Transactions on Power Electronics, pages 885-893, July 2004.  |  |  |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.